Application/Control No.	Applicant(s)/Patent under Reexamination
10/808,465	DUPUIS ET AL.
Examiner	Art Unit
Nam Huynh	2617

	SEAR	CHED	
Class	Subclass	Date	Examiner
See	Previous	5/9/2007	NTH
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INTERFERENCE SEARCHED						
Class	Subclass	Date	Examiner			
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SEARCH NOT (INCLUDING SEARCH	TES STRATEGY)
	DATE	EXMR
See EAST search notes.	2/1/2008	NTH
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